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DATE MAILED: 11/01/2005

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/865,006	05/23/2001	Krishna Parat	042390P7462D	4672
7:	590 11/01/2005		EXAM	INER
Michael A. Bernadicou			DIAZ, JOSE R	
BLAKELY, SC	OKOLOFF, TAYLOR	& ZAFMAN LLP		· · · · · ·
Seventh Floor			ART UNIT	PAPER NUMBER
12400 Wilshire Boulevard			2815	
Los Angeles, CA 90025-1026			D. 1777 144 17 777 11/01/000	

Please find below and/or attached an Office communication concerning this application or proceeding.

			H.			
	Application No.	Applicant(s)				
	09/865,006	PARAT ET AL.				
Office Action Summary	Examiner	Art Unit	-			
	José R. Díaz	2815				
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with	the correspondence address				
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period of Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICA 136(a). In no event, however, may a rep will apply and will expire SIX (6) MONTH e, cause the application to become ABAI	ATION. ly be timely filed 4S from the mailing date of this communication. NDONED (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on 16 A	ugust 2005.					
,						
, 						
closed in accordance with the practice under E	Ex parte Quayle, 1935 C.D.	11, 453 O.G. 213.				
Disposition of Claims						
4)⊠ Claim(s) 4 and 9-11 is/are pending in the appl	ication.					
4a) Of the above claim(s) is/are withdra	wn from consideration.					
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>4 and 9-11</u> is/are rejected.		•				
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and/o	or election requirement.					
Application Papers		•				
9)☐ The specification is objected to by the Examine	er.					
10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.						
Applicant may not request that any objection to the	drawing(s) be held in abeyance	e. See 37 CFR 1.85(a).				
Replacement drawing sheet(s) including the correct						
11) ☐ The oath or declaration is objected to by the E	xaminer. Note the attached	Office Action or form PTO-152.				
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:	n priority under 35 U.S.C. § 1	19(a)-(d) or (f).				
2. Certified copies of the priority document						
Copies of the certified copies of the prio	3. Copies of the certified copies of the priority documents have been received in this National Stage					
application from the International Burea	u (PCT Rule 17.2(a)).					
* See the attached detailed Office action for a list	of the certified copies not re	eceived.				
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview Su					
 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) 		Mail Date ormal Patent Application (PTO-152)				
Paper No(s)/Mail Date	6) Other:					

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 2. Claim 4 is rejected under 35 U.S.C. 102(e) as being anticipated by Inoue (US Pat. No. 6,284,624 B1).

Regarding claim 4, Inoue teaches a method comprising:

forming a trench (4) in a silicon substrate (1), said trench having one or more upper corners (see fig. 2);

growing an oxide (6) in said trench (see fig. 13);

removing all of said grown oxide (6) from said trench (see fig. 14);

growing a second oxide (23) in said trench (see fig. 15);

filling said trench with a dielectric (8) (see fig. 16);

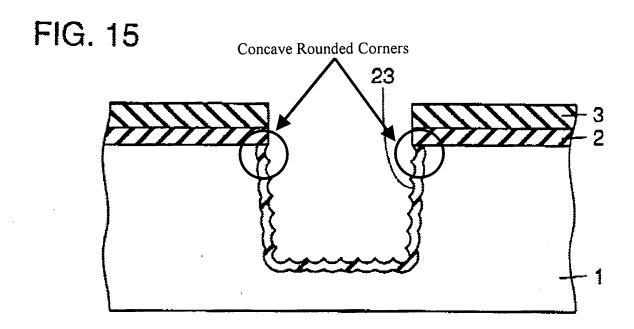
growing a tunnel oxide (10) on said silicon substrate adjacent to said dielectric filled trench (see fig. 17);

forming a first polysilicon layer (26) on said tunnel oxide (see fig. 25);

forming an intepoly dielectric (27) on said first polysilicon layer (see fig. 25);

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forming a polysilicon control gate (28) on said interpoly dielectric (see fig. 25); wherein after the growing the second oxide, the one or more upper corners of said trench are round (consider the concave rounded corners shown in figure 15, below).



3. Claims 9-11 are rejected under 35 U.S.C. 102(b) as being anticipated by Teng et al. (US Pat. No. 4,890,144).

Regarding claim 9, Teng et al. teaches a method comprising:

forming a trench (18) in a semiconductor substrate (12) between a first cell and a second cell (please consider the portions of the substrate that have isolation regions 16, which are located at the right and left sides of trench (18). See fig. 4);

forming an opening in a first dielectric material (20) in the trench (please note that layer 20 was removed to expose the bottom surface of the trench. See fig. 5 and col. 4, lined 40-41);

forming a second dielectric material (24) in the opening in the fist dielectric material (see fig. 5)

forming a shared source region (30) through the opening between the first cell and the second cell (see fig. 5);

forming sidewall spacers with the second dielectric material (24) (please note that layer 24 is patterned in figure 6 to expose the bottom surface of the trench, so that layer 24 remains only on the sidewalls of the trench).

Regarding claim 10, Teng et al. further teaches growing a thermal oxide (32) in the trench (see fig. 6).

Regarding claim 11, Teng et al. further teaches forming the second dielectric material (24) with a chemical vapor deposition (CVD) process (see col. 4, lines 40-44).

Response to Arguments

- 4. Applicant's arguments filed August 16, 2005 have been fully considered but they are not persuasive.
- 5. With regards to Inoue, applicant argued that the reference fails to teach a trench having rounded corners as now claimed. However, the examiner disagrees. Figure 15

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of Inoue clearly shows rounded corners having concave shape. Therefore, Inoue anticipates the claimed limitation.

6. With regards to Teng et al., applicant argued that region (30) is not a shared source region, as recited in claim 9. However, the examiner disagrees. Teng et al. teaches two devices (46 and 50) that share the same region (30) (fig. 15 and column 3, lines 51-52). In addition, Teng et al. teaches that region (30) is either a source or a drain region (column 3, lines 51-52). Thus, Teng et al. clearly anticipates the claimed invention by teaching a shared region that can be used as the source region for both devices.

Conclusion

7. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

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Correspondence

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to José R. Díaz whose telephone number is (571) 272-

1727. The examiner can normally be reached on Monday through Thursday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Tom Thomas can be reached on (571) 272-1664. The fax phone number

for the organization where this application or proceeding is assigned is 571-273-8300.

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SUPERVISORY PATENT EXAMINER

José R. Díaz

Examiner

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